

Prepared By: Jennifer Dimeler & Lee Schaeffer Nett Warrior Quick Disconnect Circular Plug and Receptacle Connectors Tobyhanna Army Depot Phase III Verification Testing

502-134146, Rev. C

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## 1. INTRODUCTION

## 1.1 Purpose

Testing was performed on the TE Connectivity (TE) Nett Warrior Quick Disconnect Circular Plug and Receptacle Connectors utilized in cable assemblies produced by Tobyhanna Army Depot (TYAD) to determine their conformance to the requirements of TYAD Phase III Test Plan TO-26 as defined in TE Verification Test Plans EA20140668T, Rev. C, and EA20140668T-1, Rev. A.

Verification

**Test Report** 

## 1.2 Scope

This report covers the electrical, mechanical, and environmental performance of the TE Connectivity Nett Warrior Quick Disconnect Circular Plug and Receptacle Connectors utilized in cable assemblies produced by TYAD. Testing was performed at the Harrisburg Electrical Components Test Laboratory between 23-February-2015 and 08-May-2015. Test Group 5 environmental and basic functionality testing were performed at E-Labs, Fredericksburg, VA, between 9-April-2015 and 04-May-2015. Detailed test data is on file and maintained at the Tyco Electronics Harrisburg Electrical Components Test Laboratory.

## 1.3 Conclusion

All specimens of the TE Connectivity Nett Warrior Quick Disconnect Circular Plug and Receptacle Connectors utilized in cable assemblies produced by TYAD, as listed in paragraph 1.4, conformed to the electrical, mechanical, and environmental performance requirements of Tobyhanna Army Depot (TYAD) Phase III Test Plan TO-26, as defined in TE Connectivity test plans EA20140668T, Rev. C, and EA20140668T-1, Rev. A.

## 1.4 Test Specimens

Plug and receptacle connectors are 6-position quick-disconnect circular electrical connectors. A mated connector pair measures approximately 1.5 inches long, and 0.5 inches in diameter. Five groups of test specimens, as identified in Table 1, were submitted for testing. The double-ended production cable assemblies were prepared by TYAD and are shown in Figure 1.

Test Group	Quantity	Plug P/N	Receptacle P/N	Assembly Length (inch)	Ferrite						
1	2	2226910-1	2226920-1	20	No						
2	2	2226910-1	2226920-1	20	No						
3	2	2226910-1	2226920-1	20	Yes						
4	2	2226910-1	2226920-1	20	No						
5	2	2226910-1	2226920-1	20	No						

## Table 1 – Test Specimens

To facilitate in-situ electrical testing and discontinuity monitoring, single-ended "pig-tail" support cable assemblies were prepared by TE and are shown in Figure 2. Extension leads were added as necessary to provide access into chambers.







Figure 2 – Testing Support "Pig-Tail" Cables With Extension Leads

## Figure 1 – Test Specimen Cable Configuration

## 1.5 Test Sequence

The test specimens referred to in paragraph 1.4 were tested according to the test sequences listed in Table 2.

	Test Group									
Test or Examination	1	2	3	4	5					
	Test Sequence (a)									
Visual Examination	1, 5	1, 5, 9, 13, 17, 21	1, 5, 9, 13	1, 5, 9, 13,17	1, 5, 9, 13, 17					
Voltage Drop @ 1 Adc	2	2, 6, 10, 14, 18, 22	2, 6, 10, 14	2, 6, 10, 14,18	2, 6, 10, 14, 18					
Insulation Resistance @ 500 Vdc	3	3, 7, 11, 15, 19, 23	3, 7, 11, 15	3, 7, 11, 15,19	3, 7, 11, 15, 19					
Breakaway Force	4									
Strength				16						
Altitude – Procedure I		4								
Altitude – Procedure II		8								
Vibration – Procedure I		12								
Shock		16								
Vibration – Procedure II		20								
High Temperature – Procedure II			4							
High Temperature – Procedure I			8							
Low Temperature – Procedure II			12							
Humidity – Induced Storage & Transit				4						
Humidity – Natural Environment Operational				8						
Salt Atmosphere				12						
Rain					4					
Snow & Ice					8					
Solar Radiation					12					
Dust					16					

### Table 2 – Test Sequence

(a) Numbers indicate the sequence in which tests were performed.

## 1.6 Environmental Conditions

Unless otherwise stated, the following environmental conditions prevailed during testing:

Temperature:	15°C to 35°C
Relative Humidity:	20% to 80%



## 2. SUMMARY OF TESTING

## 2.1 Visual Examination – All Groups

There was no visual evidence of physical damage. Salt deposits were observed at final examination of Test Group 4 (see Figures 3 through 6). A white residue was observed at final examination of Test Group 5 (see Figure 7 and Figure 8).



Figure 3 – Specimen 401 Plug Post Salt Spray



Figure 4 – Specimen 401 Receptacle Post Salt Spray



Figure 5 – Specimen 402 Plug Post Salt Spray



Figure 6 – Specimen 402 Receptacle Post Salt Spray



Figure 7 – White Residue on Plugs Test Group 5



Figure 8 – White Residue on Receptacles Test Group 5

## 2.2 Voltage Drop @ 1 Adc – All Groups

Voltage drop data was utilized to verify continuity at the prescribed steps in the test sequence. Measurement data for each test group is included in Appendix C of this report.

## 2.3 Insulation Resistance @ 500 Vdc – All Groups

All insulation resistance measurements were greater than the minimum requirement of 100 Megohms. Measurement data for each test group is included in Appendix D of this report.

## 2.4 Breakaway Force – Group 1

Breakaway forces met the  $13 \pm 3$  lbf requirement. See Table 3 for data.

	Table e Broakanay i eree ikee ake									
Specimen ID	Description	Maximum Force (lbf)								
101	Overmolded Receptacle + "pig-tail" Plug	10.99								
101	Overmolded Plug + "pig-tail" Receptacle	11.44								
102	Overmolded Receptacle + "pig-tail" Plug	11.26								
102	Overmolded Plug + "pig-tail" Receptacle	10.72								

Table	3 -	Breakaway	/ Force	Results
Iable	<b>J</b> –	Dicanaway		Negung

## 2.5 Strength – Group 4

There was no damage to the cable sheath or connector due to slippage of the cable connection.

### 2.6 Altitude – Procedure I – Group 2

Post altitude visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.7 Altitude – Procedure II – Group 2

No discontinuities of one microsecond or greater occurred during testing. Post altitude visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.8 Vibration – Procedure I – Group 2

No discontinuities of one microsecond or greater occurred during testing. Post vibration visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.9 Shock – Group 2

Post shock visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.10 Vibration – Procedure II – Group 2

Post vibration visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.11 High Temperature – Procedure II – Group 3

No discontinuities of one microsecond or greater occurred during testing. Voltage drop and insulation resistance were measured during the time of maximum thermal response during each of the three cycles. All visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.12 High Temperature – Procedure I – Group 3

Post high temperature exposure visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.



## 2.13 Low Temperature – Procedure II – Group 3

No discontinuities of one microsecond or greater occurred during testing. Voltage drop and insulation resistance were measured at the third hour of the exposure. All visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.14 Humidity – Induced Storage & Transit – Group 4

Post humidity visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.15 Humidity – Natural Environment Operational – Group 4

No discontinuities of one microsecond or greater occurred during testing. Post humidity visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.16 Salt Atmosphere – Group 4

Post salt spray visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.17 Rain – Group 5

No discontinuities of one microsecond or greater occurred during testing. Post rain visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

### 2.18 Snow & Ice – Group 5

No discontinuities of one microsecond or greater occurred during testing. Specimens were able to be manually unmated and mated using only standard items available in the field. (Discontinuities occurring during the unmate/mate cycle were not considered a failure.) Post snow & ice visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.19 Solar Radiation – Group 5

Post solar radiation visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.

## 2.20 Dust – Group 5

Post dust visual inspection, voltage drop and insulation resistance results are included in sections 2.1, 2.2, and 2.3, respectively.



## 3. TEST METHODS

## 3.1 Visual Examination – All Groups

Specimens were visually examined to the extent possible, using the unaided eye.

## 3.2 Voltage Drop @ 1 Adc – All Groups

Voltage drop measurements at 1 Adc current were made using a four terminal measuring technique (Figure 9 and Figure 10). The voltage drop across each of the six mated contact positions was measured using preattached probe leads. Test setup for Test Group 3 specimens measured during temperature exposures is shown in Figure 11.



Figure 9 – Voltage Drop Test Setup Test Group 1

Figure 10 – Voltage Drop Test Setup Test Groups 2, 3, 4, and 5



Figure 11 – Voltage Drop Measurement Setup in Chamber Test Group 3

## 3.3 Insulation Resistance @ 500 Vdc – All Groups

All connector positions were combined to form one series circuit. A voltage of 500 Vdc was applied between the combined series circuit and the cable/connector shield for a minimum of 1 second, and the insulation resistance measured.

Connector positions 1, 3, and 5 were combined to form one series circuit. Connector positions 2, 4, and 6 were combined to form another series circuit. A voltage of 500 Vdc was applied between the odd and even series circuits for a minimum of 1 second, and the insulation resistance measured. Test setup is shown in Figure 12.



Figure 12 – Insulation Resistance Test Setup

## 3.4 Breakaway Force – Group 1

Each mating connector pair of an overall assembly was tested individually. The "pig-tail" assembly was secured to a floating x-y-r table on the base of the tensile/compression test system. The mating end of the production cable assembly was secured to the moveable cross-head. An axial force was applied at a rate of 15 inches per minute until the connectors unmated. The maximum force was recorded. Test setup is shown in Figure 13.



Figure 13 – Breakaway Force Test Setup



## 3.5 Strength – Group 4

Each mating connector pair of the double-ended production cable test assembly was tested individually. The connector was secured to the base of the tensile/compression test system using a slotted plate fixture as shown in Figure 16. The cable was secured to the moving cross-head of the system 6 to 12 inches from the connector as shown in Figure 15. A pre-load of 80 lbf was applied using a test speed of 2 inches per minute and then 100 lbf was applied using a test speed of .5 inches per minute. 100 lbf was held for 30 seconds. Test setup is shown in Figure 14.





Figure 15 – Cable Clamp On Crosshead



Figure 16 – Connector Secured On Base

## 3.6 Altitude – Procedure I – Group 2

Storage Altitude testing was performed in accordance with MIL-STD-810G, Method 500.5, Procedure I. Mated test specimens were placed in the chamber and the pressure was adjusted to a simulated altitude of 40,000 feet. Specimens were exposed to the simulated altitude for 1 hour. Test setup is shown in Figure 17.



Figure 17 – Altitude – Procedure I Test Setup

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## 3.7 Altitude – Procedure II – Group 2

Storage Altitude testing was performed in accordance with MIL-STD-810G, Method 500.5, Procedure II. Mated test specimens were placed in the chamber and the pressure was adjusted to a simulated altitude of 32,000 feet. Specimens were exposed to the simulated altitude for 1 hour. The test specimens were monitored for discontinuities of 1 microsecond or greater using an energizing current of 100 milliamperes. Test setup is shown in Figure 18.



Figure 18 – Altitude – Procedure II Test Setup

## 3.8 Vibration – Procedure I – Group 2

The test specimens were subjected to a random vibration test in accordance with specification MIL-STD-810G, Method 514.7, Procedure I. See Figure 19 and Figure 20 for vibration setup photographs. The parameters of this test condition were specified by a random vibration spectrum with excitation frequency bounds of 20 and 2000 Hertz (Hz). The spectrum was flat at 0.04 G<sup>2</sup>/Hz from 20 Hz to 1000 Hz. The spectrum sloped down at 6 dB per octave to a PSD of 0.01 G<sup>2</sup>/Hz at the upper bound frequency of 2000 Hz. The root-mean square amplitude of the excitation was 7.7 GRMS. The test specimens were subjected to this test for 1 hour in two perpendicular axes. The longitudinal axis (mating axis) and one of the perpendicular planes to that axis, for a total test time of 2 hours per test specimen. The test specimens were monitored for discontinuities of 1 microsecond or greater using an energizing current of 100 milliamperes.





Figure 19 – Vibration Test Setup Longitudinal Axis



## 3.9 Shock – Group 2

Transit Drop Shock testing was performed in accordance with MIL-STD-810G, Method 516.6, Procedure IV. Mated test specimens were dropped from a height of 48 inches onto a concrete surface. A total of nine drops were performed on each specimen, re-orienting the assembly approximately 40 degrees from its previous orientation with each drop. Test setup is shown in Figure 21 and Figure 22.



Figure 21 – Shock Test Setup



Figure 22 – Shock Test Setup



#### 3.10 Vibration – Procedure II – Group 2

Loose cargo vibration testing was performed in accordance with MIL-STD-810G, Method 514.6, Category 5, Procedure II. Testing was performed using a package tester setup as shown in Figure 1. The length of each side was approximately 22.5 inches (based on a specimen length of approximately 20 inches and a connector diameter of approximately 0.5 inches, and using Equation (3) of MIL-STD-810G, Method 514.6, Annex C, Paragraph 2.2.c). The movement of the package tester bed was a 1.0 inch diameter orbital path at 5 Hz. Unmated double-ended production test specimens were placed in the test area in a non-uniform manner (Figure 24) and subjected to the prescribed motion for a period of 20 minutes. Test setup is shown in Figure 23.



Figure 23 – Test Setup

Figure 24 – Random Specimen Placement

#### 3.11 High Temperature – Procedure II – Group 3

Operation High Temperature testing was performed in accordance with MIL-STD-810G, Method 501.5, Procedure II. Mated test specimens were placed in the test chamber as shown in Figure 25 and subjected to three cycles of the temperature profile defined in Table 4. The test specimens were monitored for discontinuities of 1 microsecond or greater using an energizing current of 100 milliamperes.

I able 4	– Operation Hig	jn iempe	rature Profile
Hour	Temperature (Deg. C)	Hour	Temperature (Deg. C)
1	36	13	48
2	40	14	46
3	44	15	44
4	48	16	42
5	52	17	40
6	55	18	38
7	55	19	36
8	55	20	34
9	55	21	32
10	55	22	30
11	52	23	30
12	50	24	33

able 4– Operation High Temperature Profile	able 4-	Operation	High	Temperature	Profile
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Figure 25 – High Temperature Test Setup



## 3.12 High Temperature – Procedure I – Group 3

Storage High Temperature testing was performed in accordance with MIL-STD-810G, Method 501.5, Procedure I. Mated test specimens were placed in the test chamber as shown in Figure 25 and subjected to seven cycles of the temperature profile defined in Table 5.

Idale	e eteragering		
Hour	Temperature (Deg. C)	Hour	Temperature (Deg. C)
1	42	13	58
2	48	14	54
3	54	15	50
4	59	16	46
5	64	17	43
6	68	18	40
7	71	19	37
8	71	20	34
9	69	21	32
10	67	22	30
11	64	23	33
12	61	24	37

Table 5 –	Storage	High	Temperature	Profile
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## 3.13 Low Temperature – Procedure II – Group 3

Operation Low Temperature testing was performed in accordance with MIL-STD-810G, Method 502.5, Procedure II. Mated test specimens were placed in the test chamber as shown in Figure 25 and subjected to a temperature of -18°C for a period of 6 hours. The test specimens were monitored for discontinuities of 1 microsecond or greater using an energizing current of 100 milliamperes.

## 3.14 Humidity – Induced Storage & Transit – Group 4

Induced Storage and Transit Humidity testing was performed in accordance with MIL-STD-810G, Method 507.5, Procedure I. Mated specimens were placed in the chamber and subjected to three cycles of the Induced Storage and Transit temperature/humidity profile defined in Column B2 of Figure 26. Test setup is shown in Figure 27.



	Natural <sup>1</sup>									Induced (Storage & Transit)						
Time	Fime Fime (Cycle B1)		igh Humidity Cyclic High RH ) (Cycle B2)			Ho (C	Hot Humid (Cycle B3)			Constant Temp. (Cycle B1)			ic RH B2)	Hot Humid (Cycle B3)		
	Temp. 1	RH	H Temp. RH		Temp. RH Temp. RH Temp. RH		Te	mp.	RH	Te	mp.	RH				
0000	1	%	°F	°C	100	°F	°C	%		%	°F	°C	%	°F	°C	62
0100	1	<u></u>	80	27	100	00	31	00 99		100	01	33	60	05	35	67
0200	1	00	70	26	100	88	31	00 88		100	00	30	70	04	34	72
0300	1	00	70	20	100	88	31	88		100	90	32	70	04	34	75
0400	1	00	70	26	100	88	31	88		100	88	31	72	03	34	77
0500	. 1	00	78	26	100	88	31	88		100	86	30	74	92	33	79
0600		00	78	26	100	90	32	85	ours	100	88	31	75	91	33	80
0700	4 14	98	81	27	94	93	34	80	4	98	93	34	64	97	36	70
0800	16 2	97	84	29	88	96	36	76	16 2	97	101	38	54	104	40	54
0900	nt t)	95	87	31	82	98	37	73	nt t]	95	107	42	43	111	44	42
1000	gho	95	89	32	79	100	38	69	gho	95	113	45	36	124	51	31
1100	Irou	95	92	33	77	102	39	65	Irou	95	124	51	29	135	57	24
1200	Ð	95	94	34	75	104	40	62	- -	95	134	57	22	144	62	17
1300	75°	95	94	34	74	105	41	59	80°	95	142	61	21	151	66	16
1400	ů.	95	95	35	74	105	41	59	ů,	95	145	63	20	156	69	15
1500	t 24	95	95	35	74	105	41	59	t 33	95	145	63	19	160	71	14
1600	nta	95	93	34	76	105	41	59	nta	95	144	62	20	156	69	16
1700	nsta	95	92	33	79	102	39	65	nsta	95	140	60	21	151	66	18
1800	8	95	90	32	82	99	37	69	8	95	134	57	22	145	63	21
1900	carl	97	88	31	86	97	36	73	carl	97	122	50	32	136	58	29
2000	ž	98	85	29	91	94	34	79	ž	98	111	44	43	122	50	41
2100	1	00	83	28	95	91	33	85		100	101	38	54	105	41	53
2200	1	00	82	28	96	90	32	85		100	95	35	59	103	39	58
2300	1	00	81	27	100	89	32	88		100	93	34	63	99	37	62
2400	1	00	80	27	100	88	31	88		100	91	33	68	95	35	63

Figure 26 – Temperature/Humidity Profile for Induced Storage & Transit Condition



Figure 27 - HumidityTest Setup

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## 3.15 Humidity – Natural Environment Operational – Group 4

Natural Humidity testing was performed in accordance with MIL-STD-810G, Method 507.5, Procedure I. Mated specimens were placed in the chamber and subjected to three cycles of the Natural temperature/humidity profile defined in Column B2 of Figure 28. For chamber control purpose, 100% RH implies as close to 100% RH as possible, but not less than 95%. The test specimens were monitored for discontinuities of 1 microsecond or greater using an energizing current of 100 milliamperes. Test setup is shown in Figure 27.

				Natu	ral <sup>1</sup>				Induced (Storage & Transit)							
	Con	High stant	Humidity Cyclic			Ho	t Hur	nid	Con	stant		Cycl	ic PH	Hot Humid		
Time	Ter	mp.		High R	H	(C	(Cycle B3) 1 emp. (Cycle B		шр. le B1)		Cvcle	B2)	(Cycle B3)			
	(Cycl	le B1)	(	Cycle B	32)				(0)10							
	Temp	. RH	Te	mp.	RH	Ter	Temp. RH		Temp.	RH	Te	mp.	RH	Te	mp.	RH
0000		% 100 <sup>2</sup>	80	27	% 100	88	31	% 88		%0 100 <sup>2</sup>	- <b>r</b> 01	33	68	95	35	63
0100		100	80	27	100	88	31	88		100	91	33	69	95	35	67
0200		100	79	26	100	88	31	88		100	90	32	70	94	34	72
0300		100	79	26	100	88	31	88		100	90	32	71	94	34	75
0400		100	79	26	100	88	31	88		100	88	31	72	93	34	77
0500	vi	100	78	26	100	88	31	88	si	100	86	30	74	92	33	79
0600	no	100	78	26	100	90	32	85	our	100	88	31	75	91	33	80
0700	24 P	98	81	27	94	93	34	80	24 P	98	93	34	64	97	36	70
0800	the	97	84	29	88	96	36	76	the	97	101	38	54	104	40	54
0900	out	95	87	31	82	98	37	73	ont	95	107	42	43	111	44	42
1000	dan (	95	89	32	79	100	38	69	qan	95	113	45	36	124	51	31
1100	phro	95	92	33	77	102	39	65	hro	95	124	51	29	135	57	24
1200	Ē	95	94	34	75	104	40	62	Ē	95	134	57	22	144	62	17
1300	(75	95	94	34	74	105	41	59	(80)	95	142	61	21	151	66	16
1400	S.	95	95	35	74	105	41	59	S	95	145	63	20	156	69	15
1500	11 27	95	95	35	74	105	41	59	it 27	95	145	63	19	160	71	14
1600	int i	95	93	34	76	105	41	59	, it	95	144	62	20	156	69	16
1700	onst	95	92	33	79	102	39	65	ust	95	140	60	21	151	66	18
1800	y cc	95	90	32	82	99	37	69	y cc	95	134	57	22	145	63	21
1900	carl	97	88	31	86	97	36	73	carl	97	122	50	32	136	58	29
2000	Z	98	85	29	91	94	34	79	Ž	98	111	44	43	122	50	41
2100		100	83	28	95	91	33	85		100	101	38	54	105	41	53
2200		100	82	28	96	90	32	85		100	95	35	59	103	39	58
2300		100	81	27	100	89	32	88		100	93	34	63	99	37	62
2400		100	80	27	100	88	31	88		100	91	33	68	95	35	63

Figure 28 – Temperature/Humidity Profile for Natural Condition



## 3.16 Salt Atmosphere – Group 4

Salt atmosphere testing was performed in accordance with MIL-STD-810G, Method 509.5. Unmated test specimens were placed in the chamber as shown in Figure 29. Specimens were exposed to the standard salt spray conditions of 5% salt concentration at 35°C for 24 hours. Specimens were removed from the chamber and allowed to dry at ambient conditions for a period of 24 hours. Specimens were then exposed the standard salt spray conditions for another 24 hours after which they were removed from the chamber and allowed to dry at ambient conditions for a period of 24 hours.



Figure 29 – Salt Spray Test Setup

## 3.17 Rain – Group 5

Rain testing was performed in accordance with MIL-STD-810G, Method 506.5, Procedure II (Exaggerated). Mated specimens were subjected to a water spray pattern having a droplet size predominately in the 0.45 to 0.50 mm range travelling at approximately 64 km/h (40 mph) at approximately 276 kPa (40 psig). The spray was applied to all exposed surfaces of the test specimens for 40 minutes. The test specimens were monitored for discontinuities of 1 microsecond or greater using an energizing current of 100 milliamperes.

## 3.18 Snow & Ice – Group 5

Snow & Ice testing was performed in accordance with MIL-STD-810G, Method 521.3 (Glaze Ice Procedure for 6 mm Ice Thickness). Mated specimens were placed in the test chamber, and the air temperature was adjusted to 0°C (-0/+2°C) and maintained for a minimum period of 1 hour to allow the test specimens to stabilize at temperature. The specimens were then subjected to a uniform, pre-cooled (0 to 3°C) water spray at a rate of approximately 25 mm/hour for 1 hour to allow water penetration into the test specimen crevices and openings. The chamber air temperature was then adjusted to -10°C, and the water spray rate maintained until 6 millimeters of ice had accumulated on the surface of the test specimens. At that point, the chamber air temperature was maintained for a minimum period of 4 hours to allow ice to harden. The specimens were then manually unmated and mated, using only standard items available in the field. Immediately following the mating cycle, voltage drop and insulation resistance were measured in accordance with Paragraphs 3.2 and 3.3 respectively. The chamber air temperature was then adjusted to standard ambient conditions.



## 3.19 Solar Radiation – Group 5

Solar Radiation testing was performed in accordance with MIL-STD-810G, Method 505.5, Procedure I, Cycle A1, for three continuous cycles. Mated specimens were placed in the test chamber, and exposed to three continuous 24-hour cycles of controlled simulated radiation and dry-bulb temperature as indicated for Cycle A1 of Figure 30.



Figure 30 – Solar Radiation Exposure Curve

## 3.20 Dust – Group 5

Dust testing was performed in accordance with MIL-STD-810G, Method 510.5, Procedure I. Mated specimens were placed in the test chamber, and stabilized at a temperature of  $55^{\circ}$ C. The air velocity was then adjusted to 8.9 m/sec, and the dust feed control adjusted to a dust concentration of 10.6 +/- 7 g/m<sup>3</sup>. These conditions were maintained for a period of 6 hours. The dust feed was then stopped, and the air velocity was reduced to 1.5 +/- 1 m/sec while the chamber was maintained at a temperature of  $55^{\circ}$ C. These conditions were maintained for a period of 1 hour. The air velocity was then adjusted to 8.9 m/sec, and the dust feed control adjusted to a dust concentration of 10.6 +/- 7 g/m<sup>3</sup>. These conditions were maintained for a period of 1 hour. The air velocity was then adjusted to 8.9 m/sec, and the dust feed control adjusted to a dust concentration of 10.6 +/- 7 g/m<sup>3</sup>. These conditions were maintained for another period of 6 hours. The dust feed was then stopped, the test chamber was allowed to return to room ambient conditions, the air flow was stopped, and the dust was allowed to settle. Accumulated dust was removed from the test specimens by shaking and brushing prior to post-test measurements.



## 4. EQUIPMENT

## 4.1 Calibration Statement

All equipment containing a calibration number is calibrated and traceable through TE Connectivity (TE) to the National Institute of Standards and Technology (NIST).

## 4.2 Equipment List

Equipment Name	Calibration Number	
Ambient Temperature/Humidity Monitoring System	E9100-1703	
Specified Current Station #2 Multimeter	E9100-1146	
Specified Current Station #2 Power Supply	E9100-1147	
Power Supply	E9100-1810	
Shunt 50A/25mV	E9100-0653	
Digital Multimeter	E9100-1811	
Slot 1 Acquisition Module	E9100-1823	
Slot 2 Acquisition Module	E9100-1824	
Slot 3 Acquisition Module	E9100-1825	
Load Frame	E9100-1729	
Load Cell	E9100-1730	
"Pig-Tail" Connector Fixture	39-1824440	N/A
Overmolded Connector Fixture (.300" x .082" Slotted Pla	ate) N/A	
Altitude Chamber	E9100-1927	
Discontinuity Event Detector	E9100-1813	
Control Accelerometer	E9100-1262	
Dytran Accel. Power Supply	E9100-1887	
Vibration Controller	E9100-1306	
Discontinuity Event Detector	E9100-1971	
Vibration Table & Amplifier EM-1104	N/A	
Base Plate 99-466854-1	N/A	
Test Fixture 39-1824540-1	N/A	
Clamping Bars	N/A	
Metal Scale, 4 Ft.	N/A	
Temperature Cycling Chamber	E9100-1310	
Temperature - Humidity Chamber	E9100-1682	
Salt Fog Corrosion Chamber	E9100-1814	
PH Meter calibrated to three buffer solution standards	E9100-1751/1752	2/1753
Watlow F4 Process Controller	E9100-1866	
Cargo Fixture Bottom Plate	39-1824678-1	N/A
Cargo Fixture Side 39-1824679-1	N/A	



# Appendix A

## Test Plan Utilizing Outside Resources EA20140668T, Rev. C







Verification Test Plan

## EA20140668T, Rev. C

3/3/15

Prepared By: Lee W. Schaeffer

Quick Disconnect Circular Plug and Receptacle Connectors Phase III Verification Testing Utilizing Outside Resources

### 1. Test Protocol and Specimens

### 1.1 Verification Test Protocol

The test specimens shall be subjected to the verification tests in Table 1.

Test or Examination	Test Sequence <sup>1</sup>			
Visual Examination	1, 5, 9, 13, 17			
Voltage Drop @ 1 Adc	2, 6, 10, 14, 18			
Insulation Resistance @ 500 Vdc	3, 7, 11, 15, 19			
Rain	4			
Snow & Ice <sup>2</sup>	8			
Solar Radiation	12			
Dust	16			

Note 1: Numbers indicate sequence in which tests are to be performed. Note 2: Snow & loe test requires insitu Voltage Drop and Insulation Resistance measurements in addition to post-test measurements. See Paragraph 2.5.

### 1.2 Test Specimen Quantities

The test specimens shall be allocated to as indicated in Table 2.

Table 2 -	Test Specin	nen Quantities
Test Group	Cable Assembly Qty	Component Type
	2	Plug
9	2	Receptacle

## 1.3 Test Specimen Configuration

Plug and receptacle connectors are 6-position quick-disconnect circular electrical connectors. A mated connector pair measures approximately 1.5 inches long, and 0.5 inches in diameter. The cabled configuration submitted for testing is as follows:

 6-position plug and receptacle "pig-tail" specimens in Test Groups 1, 3, and 4 will be terminated with approximately 8 inches of appropriate 6-conductor cable. The "pig-tail" specimens will be mated to double-ended production cable assemblies approximately 20 inches in length. The overall assemblies will be pre-wired into two series circuits. Series circuit #1 shall consist of the three odd numbered contact positions (1, 3, and 5), wired to form one series circuit. Series circuit #2 shall consist of the three even numbered contact positions (2, 4, and 6), wired to form a second series circuit.

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### 2. Test Methods

Tests shall be performed at a temperature of 15°C to 35°C and at 20% to 80% relative humidity, unless otherwise indicated. Tolerances on time intervals shall be +/-5% unless otherwise indicated. Tolerances on test current shall be +/- 2% unless otherwise indicated.

### 2.1 Visual Examination

### Method

Specimens shall be visually examined to the extent possible. Document any visual evidence of physical damage.

### Requirement

No visual evidence of physical damage.

### 2.2 Voltage Drop @ 1 Adc

### Method

Series circuits #1 and #2 shall be combined to form one series circuit. The combined series circuit shall be energized at 1 Adc. The voltage drop across each of the six mated contact positions shall be measured using the pre-attached probe leads.

### Requirement

No requirement defined. Provide all measured data.

### 2.3 Insulation Resistance @ 500 Vdc

### Measurement A - All Contact Positions to Shield

Series circuits #1 and #2 shall be combined to form one series circuit. A voltage of 500 Vdc shall be applied between the combined series circuit and the cable/connector shield for a minimum of 1 second, and the insulation resistance measured.

### Measurement B - Between Contact Positions

Series circuits #1 and #2 shall be separated into their two pre-wired series circuits. A voltage of 500 Vdc shall be applied between series circuits #1 and #2 for a minimum of 1 second, and the insulation resistance measured.

### Requirement

Insulation Resistance measurements at 500 Vdc shall be greater than the minimum requirement of 100 Megohms. Provide all measured data.

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### 2.4 Rain

### Method

Rain testing shall be performed in accordance with MIL-STD-810G, Method 506.5, Procedure II (Exaggerated). The test procedures shall be as follows:

- Combine series circuits #1 and #2 to form one series circuit. During testing, monitor the series circuit for discontinuities greater than 1 microsecond using a test current of 100 milliamperes. Discontinuities occurring during intentional unmating of the test item shall not be considered a failure.
- Use a nozzle that produces a spray pattern with a droplet size predominately in the 0.45 mm to 0.5 mm range travelling at approximately 64 km/h (40 mph) at approximately 276 kPa (40 psig).
- 3. Spray all exposed surfaces of the test item for 40 minutes.
- Unmate the test item, inspect the interior of the item for evidence of moisture ingress. If no moisture present, mate the test item and proceed.
- Perform Steps 1 through 3 in two orthogonal axes perpendicular to the long axis of the connector, for a total of two cycles.

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

### 2.5 Snow and Ice

### Method

Snow and Ice testing shall be performed in accordance with MIL-STD-810G, Method 521.3, Glaze Ice Procedure for 6 millimeter Ice Thickness. The test procedure shall be as follows:

- Combine series circuits #1 and #2 to form one series circuit. During testing, monitor the series circuit for discontinuities greater than 1 microsecond using a test current of 100 milliamperes. Discontinuities occurring during intentional unmating of the test item shall not be considered a failure.
- Place the mated test specimens in the test chamber, adjust the air temperature to 0°C (-0 / +2°C), and maintain for a minimum of 1 hour to allow test specimens to stabilize at temperature.
- Deliver a uniform, pre-cooled (0 to 3°C) water spray at a rate of approximately 25 mm/hour for 1 hour to allow water penetration into the test specimen crevices/openings.
- 4. Adjust the chamber air temperature to -10°C, and maintain the water spray rate until 6 millimeters of ice has accumulated on the surface of the test specimens. Wind or a side spray may be used to assist accumulation of ice on the sides of the test item.
- 5. Maintain the chamber air temperature for a minimum period of 4 hours to allow ice to harden.
- Manually unmate and remate each mated test specimen. The operator may remove the amount of ice necessary to accomplish the unmate/remate cycle using only standard items available in the field. Immediately following the mating cycle, complete the following:

   Measure the voltage drop in accordance with Paragraph 2.2.
  - Measure the voltage drop in accordance with Paragraph 2.2.
     Measure the insulation resistance in accordance with Paragraph 2.3.
- Adjust the chamber air temperature to standard ambient conditions.

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### 2.5 Snow and Ice (cont.)

Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

### 2.6 Solar Radiation

### Method

Solar Radiation testing shall be performed in accordance with MIL-STD-810G, Method 505.5, Procedure I, Cycle A1, for three continuous cycles. The test procedure shall be as follows:

- Place the mated test specimen in the test chamber, and adjust the air temperature to the minimum value of the temperature cycle at which radiation is nonexistent.
- Expose the test specimen to three continuous 24-hour cycles of controlled simulated radiation and dry-bulb temperature as indicated for Cycle A1 of Figure 1.
- 3. Adjust the chamber air temperature to standard ambient conditions.

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.



Figure 1 – Solar Radiation Exposure Curve

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### 2.7 Dust

### Method

Dust testing shall be performed in accordance with MIL-STD-810G, Method 510.5, Procedure I. The test procedures shall be as follows:

Procedure I - Blowing Dust (Red China Clay or Silicon Flour)

- Place the mated test specimens in the chamber, and stabilize at a temperature of 55°C. Adjust the air velocity to 8.9 m/sec.
- 2. Adjust the dust feed control for a dust concentration of 10.6 +/- 7 g/m3.
- 3. Maintain the conditions of Steps 1 and 2 for a period of 6 hours.
- Stop the dust feed. Reduce the test section air velocity to 1.5 +/- 1 m/sec, and maintain the temperature at 55°C.
- 5. Maintain the conditions of Step 4 for a period of 1 hour.
- Adjust the air velocity to 8.9 m/sec, and adjust the dust feed control for a dust concentration of 10.6 +/- 7 g/m<sup>3</sup>.
- 7. Maintain the conditions of Step 6 for a period of 6 hours.
- Stop the dust feed, and allow the test item to return to standard ambient conditions at a rate not to exceed 3°C/min. Stop any air flow, and allow the dust to settle.
- Remove accumulated dust from the test specimens by brushing, wiping, or shaking. Do not remove dust by either air blast or vacuum cleaning.

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

### 3. Documentation Requirements

Documentation of each test performed shall be provided, and shall include, as a minimum, the following:

- 1. Title of test report.
- A unique identification number for the report, and on each page an identification in order to ensure that the page is recognized as a part of the test report.
- 3. The name and location of the test laboratory performing the testing.
- 4. The name of the person(s) issuing the report.
- 5. The name of the test requester (TE Connectivity).
- 6. Date(s) test performed.
- 7. Name(s) of operator(s).
- 8. Ambient temperature and humidity at time of test.
- 9. Description(s) of the item(s) tested.
- Statement of results, including measured values (if applicable), any observations and/or anomalies, and results of final visual examination. Where damage or anomalies are observed, photographs shall be included.
- 11. Detailed description of test procedure, including a statement of all test parameters.
- List of all equipment used, including manufacturer, model number, date of last calibration and calibration interval.

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### 4. Outsourcing of Testing

Outsourcing of testing to a third party test laboratory shall not be performed without advance approval of the TE Connectivity Contact Person identified in this test plan.

### 5. Laboratory Certification

Testing shall be performed at an ISO 17025 and/or ISO 9001 certified laboratory unless otherwise authorized by the TE Connectivity Contact Person identified in this test plan. A copy of the laboratory's authorization certificate(s) shall be provided prior to the start of testing.

### 6. Contact Information

Contact Person:	Lee W. Schaeffer
	Manager, Test Engineering
	Harrisburg Electrical Components Test Laboratory
	TE Connectivity
	(717) 810-3536
	lwschaef@te.com
Street Address:	TE Connectivity
	2100 Paxton Street
	Harrisburg, PA 17111
Mailing Address:	TE Connectivity
States of the second	M.S. 018-001
	P.O. Box 3608
	Harrisburg, PA 17105

### 7. Revision Record

### Table 3 – Revision Record

Level	Description of Change	Date
A	Original Release	11/20/14
в	Complete revision to test plan in accordance with revised customer requirements.	12/19/14
C Revise Test Specimen Configuration description. Change Voltage Drop test current from 3 Adc to 1 Adc.		3/3/15

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# Appendix B

## Test Plan Utilizing the TE Connectivity Harrisburg Electrical Components Test Laboratory (HECTL) Resources EA20140668T-1, Rev. A





Verification Test Plan

## EA20140668T-1, Rev. A

3/2/15

Prepared By: Lee W. Schaeffer

## Quick Disconnect Circular Plug and Receptacle Connectors Phase III Verification Testing Utilizing HECTL Resources

## 1. Test Protocol and Specimens

### 1.1 Verification Test Protocol

The test specimens shall be subjected to the verification tests in Table 1.

Test or Examination	Test Sequence <sup>1</sup>										
	Test Group 1	Test Group 2	Test Group 3	Test Group 4							
Visual Examination	1, 5	1, 5, 9, 13, 17, 21	1, 5, 9, 13	1, 5, 9, 13, 17							
Voltage Drop @ 1 Adc	2	2, 6, 10, 14, 18, 22	2, 6, 10, 14	2, 6, 10, 14, 18							
Insulation Resistance @ 500 Vdc	3	3, 7, 11, 15, 19, 23	3, 7, 11, 15	3, 7, 11, 15, 19							
Breakaway Force	4			16							
Strength				0							
Altitude – Procedure I		4									
Altitude – Procedure II	5 5	8		о. У							
Vibration - Procedure I		12									
Vibration - Procedure II		16									
Shock		20									
High Temperature – Procedure II			4								
High Temperature – Procedure I			8								
Low Temperature – Procedure II			12								
Humidity – Induced Storage & Transit				4							
Humidity – Natural Environment Operational				8							
Salt Spray				12							

Note 1: Numbers indicate sequence in which tests are to be performed.

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### 1.2 Test Specimen Quantities

The test specimens shall be allocated to as indicated in Table 2.

Test Group	Cable Assembly Qty	Component Type
1	2	Plug
	2	Receptacle
	2	Plug
2	2	Receptacle
	2	Plug
3	2	Receptacle
4	2	Plug
	2	Receptacle

### 1.3 Test Specimen Configuration

Plug and receptacle connectors are 6-position quick-disconnect circular electrical connectors. A mated connector pair measures approximately 1.5 inches long, and 0.5 inches in diameter. The cabled configuration submitted for testing is as follows:

- 6-position plug and receptacle "pig-tail" specimens in Test Groups 1, 3, and 4 will be terminated with approximately 8 inches of appropriate 6-conductor cable. The "pig-tail" specimens will be mated to double-ended production cable assemblies approximately 20 inches in length. The overall assemblies will be pre-wired into two series circuits. Series circuit #1 shall consist of the three odd numbered contact positions (1, 3, and 5), wired to form one series circuit. Series circuit #2 shall consist of the three even numbered contact positions (2, 4, and 6), wired to form a second series circuit.
- 6-position plug and receptacle "pig-tail" specimens in Test Group 2 will be terminated with approximately 12 inches of appropriate 6-conductor cable. The "pig-tail" specimens will be mated to double-ended production cable assemblies approximately 20 inches in length. The overall assemblies will be pre-wired into two series circuits. Series circuit #1 shall consist of the three odd numbered contact positions (1, 3, and 5), wired to form one series circuit. Series circuit #2 shall consist of the three even numbered contact positions (2, 4, and 6), wired to form a second series circuit.

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### 2. Test Methods

Tests shall be performed at a temperature of 15°C to 35°C and at 20% to 80% relative humidity, unless otherwise indicated. Tolerances on time intervals shall be +/-5% unless otherwise indicated. Tolerances on test current shall be +/- 2% unless otherwise indicated.

### 2.1 Visual Examination

### Method

Specimens shall be visually examined to the extent possible. Document any visual evidence of physical damage.

### Requirement

No visual evidence of physical damage.

### 2.2 Voltage Drop @ 1 Adc

### Method

Series circuits #1 and #2 shall be combined to form one series circuit. The combined series circuit shall be energized at 1 Adc. The voltage drop across each of the six mated contact positions shall be measured using the pre-attached probe leads.

### Requirement

No requirement defined. Provide all measured data.

### 2.3 Insulation Resistance @ 500 Vdc

### Measurement A – All Contact Positions to Shield

Series circuits #1 and #2 shall be combined to form one series circuit. A voltage of 500 Vdc shall be applied between the combined series circuit and the cable/connector shield for a minimum of 1 second, and the insulation resistance measured.

### Measurement B - Between Contact Positions

Series circuits #1 and #2 shall be separated into their two pre-wired series circuits. A voltage of 500 Vdc shall be applied between series circuits #1 and #2 for a minimum of 1 second, and the insulation resistance measured.

### Requirement

Insulation Resistance measurements at 500 Vdc shall be greater than the minimum requirement of 100 Megohms. Provide all measured data.

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### 2.4 Breakaway Force

### Method

- 1. Test each mating connector pair of an overall assembly individually.
- Secure the "pig-tail" assembly to the base of a Tensile/Compression test system, and secure the mating end of the production cable assembly to the moving cross-head.
- 3. Apply an axial force to the mated assembly until the connectors unmate.
- 4. Record the maximum force as the Breakaway Force.

### Requirement

1. The Breakaway Force shall be 13 +/- 3 pounds.

### 2.5 Strength

## Method

- 1. Test each connector of a double-ended production assembly individually.
- Secure the connector to the base of a Tensile/Compression test system, and secure the cable to the moving cross-head 6 to 12 inches from the connector.
- 3. Apply an axial force of 100 pounds assembly, and hold for 30 seconds.

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

### 2.6 Altitude – Procedure I (Storage)

#### Method

Storage Altitude testing shall be performed in accordance with MIL-STD-810G, Method 500.5, Procedure I. The test procedure shall be as follows:

- Place the mated test specimens in the test chamber, and adjust the pressure to a simulated altitude of 40,000 feet.
- 2. Expose the test specimen to the simulated altitude for 1 hour.

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

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### 2.7 Altitude – Procedure II (Operational)

### Method

Operational Altitude testing shall be performed in accordance with MIL-STD-810G, Method 500.5, Procedure II. The test procedure shall be as follows:

- Place the mated test specimens in the test chamber, and adjust the pressure to a simulated altitude of 32,000 feet.
- Expose the test specimen to the simulated altitude for 1 hour. During the exposure, monitor for discontinuities greater than 1 microsecond.

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

### 2.8 Vibration – Procedure I (General Vibration)

### Method

General Vibration testing shall be performed in accordance with MIL-STD-810G, Method 514.6, Annex E, Procedure I. The test procedure shall be as follows:

- Secure each mated end of the production cable assembly in the vibration fixture. Secure both
  the cable of the production cable assembly and the cables of the "pig-tail" assemblies to nonvibrating surfaces approximately 8" from the mated connectors.
- Subject the specimens to the vibration profile illustrated in Figure 1 (20 to 2000 Hz, 7.7 grms) for 1 hour in both the lateral and longitudinal axes, for a total vibration duration of 2 hours. During the test, monitor for discontinuities greater than 1 microsecond.
- Following the first axis, measure the Voltage Drop and Insulation Resistance, per Paragraphs 2.2 and 2.3 respectively.



### Figure 1 – Vibration Profile

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### 2.8 Vibration – Procedure I (General Vibration) – (cont.)

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

### 2.9 Vibration – Procedure II (Loose Cargo)

### Method

Loose Cargo Vibration testing shall be performed in accordance with MIL-STD-810G, Method 514.6, Category 5, Procedure II, for 20 minutes. The test procedure shall be as follows:

- Testing shall be performed using a package tester setup in accordance with Figure 2. The length of each side of the square test area shall be approximately 21.75 inches. (Based on a production assembly test specimen length of approximately 20 inches and a connector diameter of approximately 0.5 inches, and using Equation (3) of MIL-STD-810G, Method 514.6, Annex C, Paragraph 2.2.c.) The movement of the package tester bed shall be a 1.0 inch diameter orbital path at 5 Hz.
- Place the unmated production assembly test specimens in the test area in a non-uniform manner, and subject them to the prescribed motion for a period of 20 minutes.
- Visually examine the mated test specimens to the extent possible. Document any evidence of physical damage.



Figure 2 - Category 5 - Loose Cargo Test Setup

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

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### 2.10 Shock (Transit Drop)

### Method

Transit Drop Shock testing shall be performed in accordance with MIL-STD-810G, Method 516.6, Procedure IV. The test procedure shall be as follows:

- 1. Drop the mated test specimens from a height of 48 inches onto a concrete surface.
- Perform a total of nine drops, re-orienting the assembly approximately 40 degrees from its previous orientation with each drop.

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

### 2.11 High Temperature – Procedure II (Operation)

### Method

Operation High Temperature testing shall be performed in accordance with MIL-STD-810G, Method 501.5, Procedure II. The test procedure shall be as follows:

- Place the mated test specimens in the test chamber, and subject them to three cycles of the temperature profile defined in Table 3.
- 2. During the exposure, monitor for discontinuities greater than 1 microsecond.
- During each cycle, measure the Voltage Drop and Insulation Resistance, per Paragraphs 2.2 and 2.3 respectively, during the time of maximum thermal response.

Hour	Temperature (Deg. C)	Hour	Temperature (Deg. C)		
1	36	13	48		
2	40	14	46		
3	44	15	44		
4	48	16	42		
5	52	17	40		
6	55	18	38		
7	55	19	36		
8	55	20	34		
9	55	21	32		
10	55	22	30		
11	52	23	30		
12	50	24	33		

## Table 3 – Operation High Temperature Profile

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

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### 2.12 High Temperature – Procedure I (Storage)

### Method

Storage High Temperature testing shall be performed in accordance with MIL-STD-810G, Method 501.5, Procedure I. The test procedure shall be as follows:

 Place the mated test specimens in the test chamber, and subject them to seven cycles of the temperature profile defined in Table 4.

Hour	Temperature (Deg. C)	Hour	Temperature (Deg. C)		
1	42	13	58		
2	48	14	54		
3	54	15	50		
4	59	16	46		
5	64	17	43		
6	68	18	40		
7	71	19	37		
8	71	20	34		
9	69	21	32		
10	67	22	30		
11	64	23	33		
12	61	24	37		

Table 4 -	Storage	High	Temperature	Profile
Table 4	Storage	1115411	remperature	FIOINE

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

### 2.13 Low Temperature – Procedure II (Operation)

### Method

Operation Low Temperature testing shall be performed in accordance with MIL-STD-810G, Method 502.5, Procedure II. The test procedure shall be as follows:

- Place the mated test specimens in the test chamber, and subject them to a temperature of -18 deg. C for a period of six hours.
- 2. During the exposure, monitor for discontinuities greater than 1 microsecond.
- At hour three of the six hour exposure, measure the Voltage Drop and Insulation Resistance, per Paragraphs 2.2 and 2.3 respectively, during the time of maximum thermal response.

Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

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### 2.14 Humidity – Procedure I (Induced Storage and Transit)

### Method

Induced Storage and Transit Humidity testing shall be performed in accordance with MIL-STD-810G, Method 507.5, Procedure I. The test procedure shall be as follows:

 Place the mated test specimens in the test chamber, and subject them to three cycles of the Induced Storage and Transit temperature/humidity profile defined in Column B2 of Figure 3.

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

### 2.15 Humidity – Procedure I (Natural - Operational)

### Method

Natural Humidity testing shall be performed in accordance with MIL-STD-810G, Method 507.5, Procedure I. The test procedure shall be as follows:

- Place the mated test specimens in the test chamber, and subject them to three cycles of the Natural temperature/humidity profile defined in Column B2 of Figure 3.
- 2. During the exposure, monitor for discontinuities greater than 1 microsecond.

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

### 2.16 Salt Atmosphere

### Method

Salt Atmosphere testing shall be performed in accordance with MIL-STD-810G, Method 509.5. The test procedure shall be as follows:

- 1. Place the unmated test specimens in the test chamber.
- Expose the test specimen to the standard salt spray conditions of 5% salt concentration at 35 deg. C for 24 hours.
- Remove the specimens from the chamber, and allow to dry at ambient conditions for a period of 24 hours.
- 4. Repeat steps 1 through 3.

### Post-Test Requirement

- 1. Visual Examination in accordance with Paragraph 2.1.
- 2. Voltage Drop in accordance with Paragraph 2.2.
- 3. Insulation Resistance in accordance with Paragraph 2.3.

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	Natural						Induced (Storage & Transit)									
		High	Hum	idity		5000	ALC: NO.	1492		1000		~			0.250	1000
Time	Con Ter (Cyc	stant mp. le B1)		Cyclic High R Cycle E	н Н 12)	H(()	ot Hui Sycle E	nid 33)	Cor Te (Cyc	istant mp. de B1)		High I Cycle	RH B2)	H ()	ot Hu Cycle	mid B3)
	Temp	RH	Te	mp.	RH	Te	mp.	RH	Temp.	RH	Te	mp.	RH	Te	mp.	RH
0000	2	%	°F	°C	%	°F	°C	%	3	%	°F	°C	%	*F	°C	%
0000		100-	80	27	100	88	31	88		100-	91	33	68	95	35	63
0100		100	80	27	100	88	31	88		100	91	33	09	95	35	07
0200		100	79	26	100	88	31	88		100	90	32	70	94	34	72
0300		100	79	26	100	88	31	88		100	90	32	71	94	34	75
0400		100	79	26	100	88	31	88		100	88	31	72	93	34	77
0500	ph.	100	78	26	100	88	31	88	26	100	86	30	74	92	33	79
0600	mot	100	78	26	100	90	32	85	noc	100	88	31	75	91	33	80
0700	5	98	81	27	94	93	34	80	5	98	93	34	64	97	36	70
0800	pic line	97	84	29	88	96	36	76	the	97	101	38	54	104	40	54
0900	out	95	87	31	82	98	37	73	out	95	107	42	43	111	44	42
1000	da	95	89	32	79	100	38	69	- Ha	95	113	45	36	124	51	31
1100	ILO	95	92	33	77	102	39	65	ILOI	95	124	51	29	135	57	24
1200	E	95	94	34	75	104	40	62	E	95	134	57	22	144	62	17
1300	750	95	94	34	74	105	41	59	80.	95	142	61	21	151	66	16
1400	S.	95	95	35	74	105	41	59	C.	95	145	63	20	156	69	15
1500	1 24	95	95	35	74	105	41	59	121	95	145	63	19	160	71	14
1600	ot a	95	93	34	76	105	41	59	ut a	95	144	62	20	156	69	16
1700	Ista	95	92	33	79	102	39	65	Ista	95	140	60	21	151	66	18
1800	00	95	90	32	82	99	37	69	COL	95	134	57	22	145	63	21
1900	arly	97	88	31	86	97	36	73	arly	97	122	50	32	136	58	29
2000	Ne	98	85	29	91	94	34	79	Ne	98	111	44	43	122	50	41
2100	2742	100	83	28	95	91	33	85		100	101	38	54	105	41	53
2200		100	82	28	96	90	32	85		100	95	35	59	103	39	58
2300		100	81	27	100	89	32	88		100	93	34	63	99	37	62
2400		100	80	27	100	88	31	88		100	91	33	68	95	35	63

Figure 3 - Temperature/Humidity Profile for Natural and Induced (Storage & Transit) Conditions

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### 3. Documentation Requirements

Documentation of each test performed shall be provided, and shall include, as a minimum, the following:

- 1. Title of test report.
- A unique identification number for the report, and on each page an identification in order to ensure that the page is recognized as a part of the test report.
- 3. The name and location of the test laboratory performing the testing.
- 4. The name of the person(s) issuing the report.
- 5. The name of the test requester (TE Connectivity).
- 6. Date(s) test performed.
- 7. Name(s) of operator(s).
- 8. Ambient temperature and humidity at time of test.
- 9. Description(s) of the item(s) tested.
- Statement of results, including measured values (if applicable), any observations and/or anomalies, and results of final visual examination. Where damage or anomalies are observed, photographs shall be included.
- 11. Detailed description of test procedure, including a statement of all test parameters.
- List of all equipment used, including manufacturer, model number, date of last calibration and calibration interval.

### 4. Outsourcing of Testing

Outsourcing of testing to a third party test laboratory shall not be performed without advance approval of the TE Connectivity Contact Person identified in this test plan.

### 5. Laboratory Certification

Testing shall be performed at an ISO 17025 and/or ISO 9001 certified laboratory unless otherwise authorized by the TE Connectivity Contact Person identified in this test plan. A copy of the laboratory's authorization certificate(s) shall be provided prior to the start of testing.

### 6. Contact Information

Contact Person:	Lee W. Schaeffer Manager, Test Engineering Harrisburg Electrical Components Test Laboratory TE Connectivity (717) 810-3536 <u>wschaef@te.com</u>
Street Address:	TE Connectivity 2100 Paxton Street Harrisburg, PA 17111
Mailing Address:	TE Connectivity M.S. 018-001 P.O. Box 3608 Harrisburg, PA 17105

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## 7. Revision Record

Table 3 – Revision Record				
Revision Level	Description of Change	Date		
A	Original Release	3/2/15		

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# Appendix C

Voltage Drop @ 1 Adc Test Results



## Appendix C – Voltage Drop @ 1 Adc

Table C.1 – Test Group 1, Voltage Drop at 1 Ad	: (Units:	millivolts)
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Connector	Initial				
Position	101	102			
1	59	58			
2	56	56			
3	57	56			
4	127	127			
5	132	131			
6	56	56			

## Table C.2 – Test Group 2, Voltage Drop at 1 Adc (Units: millivolts)

Connector	Initial		Post Altitude Procedure I		Post Altitude Procedure II	
Position	201	202	201	202	201	202
1	69	69	69	69	69	69
2	70	70	70	70	70	70
3	68	68	68	68	68	68
4	154	154	153	154	154	154
5	160	160	159	159	159	160
6	69	69	69	69	69	69
	Post Vibration Procedure I					
Connector	Post Vi Proce	bration dure l	Post	Shock	Post Vi Proce	bration dure II
Connector Position	Post Vi Proce 201	bration dure l 202	Post \$ 201	Shock 202	Post Vi Proce 201	bration dure II 202
Connector Position	Post Vi Proce 201 69	bration dure l 202 69	Post \$ 201 69	Shock 202 69	Post Vi Proce 201 69	bration dure II 202 69
Connector Position	Post Vi Proce 201 69 70	bration dure I 202 69 70	Post \$ 201 69 70	Shock 202 69 70	Post Vi Proce 201 69 70	bration dure II 202 69 70
Connector Position	Post Vi Proce 201 69 70 68	bration dure I 202 69 70 68	Post \$ 201 69 70 68	Shock 202 69 70 68	Post Vi Proce 201 69 70 68	bration dure II 202 69 70 68
Connector Position 1 2 3 4	Post Vi           Proce           201           69           70           68           153	bration dure I 202 69 70 68 154	Post \$ 201 69 70 68 154	202         69           70         68           155         155	Post Vi           Proce           201           69           70           68           154	bration dure II 69 70 68 154
Connector Position 1 2 3 4 5	Post Vi           Proce           201           69           70           68           153           159	bration dure I 202 69 70 68 154 160	Post \$ 201 69 70 68 154 160	202         69           70         68           155         160	Post Vi           Proce           201           69           70           68           154           159	bration dure II 69 70 68 154 160

## Table C.3 – Test Group 3, Voltage Drop at 1 Adc (Units: millivolts)

Connector Position	Connector Initial		Post High Temp Procedure II		Post High Temp Procedure I		Post Low Temp Procedure II	
1 OSITION	301	302	301	302	301	302	301	302
1	58	58	58	58	57	58	58	58
2	59	60	59	60	59	59	59	60
3	58	57	58	58	57	57	58	58
4	128	129	129	129	127	128	128	129
5	132	133	132	134	131	132	132	134
6	57	58	57	58	57	57	57	58

## Table C.4 – Test Group 3, Voltage Drop at 1 Adc During Exposure (Units: millivolts)

Connector Position	Cycle 1 High Temp Procedure II		Cycle 2 High Temp Procedure II		Cycle 3 High Temp Procedure II		Hour 3 Low Temp Procedure II	
FOSILION	301	302	301	302	301	302	301	302
1	64	64	64	64	64	64	49	50
2	65	66	65	66	65	66	50	51
3	64	63	64	64	64	64	49	49
4	142	143	142	143	143	143	108	108
5	146	148	147	148	147	148	111	112
6	63	64	63	64	63	64	49	49

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## Appendix C – Voltage Drop @ 1 Adc (continued)

Connector Initial Position 401	Initial		Post Humidity Storage		Post Humidity Operational		Post Salt Spray		Post Strength Test	
	402	401	402	401	402	401	402	401	402	
1	58	57	58	57	58	57	58	57	58	57
2	58	58	58	58	61	58	59	58	59	59
3	57	56	57	56	57	56	57	56	57	57
4	127	127	126	127	127	127	127	127	128	128
5	131	131	131	131	131	131	131	131	132	132
6	57	57	57	57	57	57	57	57	57	57

Table C.5 – Test Group 4, Voltage Drop at 1 Adc (Units: millivolts)

Table C.6 – Test Group 5, Voltage Drop at 1 Adc (Units: millivolts)

Compositor	Ini	tial	Ini	tial	Po	ost	Po	st
Connector	@ TE Co	nnectivity	@ E-Labs, Inc.		Ra	ain	Snow & Ice	
rosition	501	502	501	502	501	502	501	502
1	56	57	56	56	57	57	57	54
2	56	58	56	57	56	58	56	56
3	56	56	58	56	56	56	57	56
4	124	126	123	124	127	125	130	130
5	126	130	125	128	127	129	129	129
6	56	57	55	55	55	56	58	58
Compositor	Po	ost	Po	ost	Fii	nal		
Connector	Po Solar Ra	ost adiation	Po Di	ost ust	Fii @ TE Co	nal nnectivity		
Connector Position	Po Solar Ra 501	ost adiation 502	Pc Di 501	ost Ist 502	Fii @ TE Coi 501	nal nnectivity 502		
Connector Position	Pc Solar Ra 501 55	ost adiation 502 211	Pc Du 501 56	ost Jst 502 114	Fin @ TE Con 501 56	nal nnectivity 502		
Connector Position	Pc Solar R 501 55 58	<b>st</b> adiation 502 211 82	Pc Du 501 56 56	ost ust 502 114 86	Fii @ TE Col 501 56 57	nal nnectivity 502 56 58		
Connector Position 1 2 3	Pc Solar R 501 55 58 58 56	<b>st</b> adiation 502 211 82 100	Pc Du 501 56 56 56	<b>502</b> 114 86 3	Fil @ TE Col 501 56 57 56	nal nectivity 502 56 58 58 56		
Connector Position 1 2 3 4	Pc Solar R 501 55 58 56 116	St           adiation           502           211           82           100           99	Pc Du 56 56 56 56 123	<b>502</b> 114 86 3 95	Fil @ TE Con 501 56 57 56 124	<b>502</b> 56 58 56 56 56 126		
Connector Position 1 2 3 4 5	Pc Solar R: 551 55 58 56 116 125	St           adiation           502           211           82           100           99           127	Pc Du 56 56 56 123 125	<b>502</b> 114 86 3 95 127	Fil @ TE Con 501 56 57 56 124 125	<b>502</b> 56 58 56 56 126 130		

Note: Specimen 502 began to exhibit erratic voltage drop results following the Solar Radiation testing. It was suspected that water ingress into the unsealed single-ended "pig-tail" support cable assemblies (see Figure C.1) compromised the integrity of the wire terminations of those assemblies. Upon return of the test specimens from E-Labs to TE Connectivity, the TYAD production cable assemblies were mated to unconditioned single-ended "pig-tail" support cable assemblies, and voltage drop measurements were taken. The results were in line with the initial measurements, confirming that the unsealed single-ended "pig-tail" support cable assemblies were the root cause of the erratic results.



Figure C.1 – Unsealed Single-Ended "Pig-Tail" Support Cable Assembly



# Appendix D

Insulation Resistance Test Results



## Appendix D – Insulation Resistance

Table D.1 – 1	Test Group 1, Ir	sulation Resistance	(Units: Mego	hms)

Measurement	Initial				
ID	101	102			
Odd – Even	7.4 x 10 <sup>4</sup>	9.9 x 10 <sup>4</sup>			
All – Sheild	5.8 x 10 <sup>4</sup>	8.2 x 10 <sup>4</sup>			

## Table D.2 – Test Group 2, Insulation Resistance (Units: Megohms)

Measurement	Ini	tial	Post A Proce	ltitude dure l	Post Altitude Procedure II		
ID	201	202	201	202	201	202	
Odd – Even	5.6 x 10 <sup>4</sup>	4.4 x 10 <sup>4</sup>	4.4 x 10 <sup>4</sup>	4.2 x 10 <sup>4</sup>	3.3 x 10 <sup>4</sup>	4.0 x 10 <sup>4</sup>	
All – Sheild	2.4 x 10 <sup>4</sup>	2.3 x 10 <sup>4</sup>	1.9 x 104	2.1 x 10 <sup>4</sup>	1.7 x 10 <sup>4</sup>	2.5 x 10 <sup>4</sup>	
	Post Vibration Procedure I						
Measurement	Post Vi Proce	bration dure l	Post	Shock	Post Vi Proce	bration dure II	
Measurement ID	Post Vi Proce 201	bration dure l 202	Post \$	Shock 202	Post Vi Proce 201	bration dure II 202	
Measurement ID Odd – Even	Post Vi Proce 201 4.3 x 10 <sup>4</sup>	bration dure I 202 4.4 x 10 <sup>4</sup>	<b>Post \$</b> <b>201</b> 3.4 x 10 <sup>4</sup>	Shock 202 2.7 x 10 <sup>4</sup>	Post Vi Proce 201 2.7 x 10 <sup>4</sup>	bration dure II 2.5 x 10 <sup>4</sup>	

## Table D.3 - Test Group 3, Insulation Resistance (Units: Megohms)

Measurement	Initial		ement Initial Post High Temp Procedure II		Post High Temp Procedure I		Post Low Temp Procedure II	
	301	302	301	302	301	302	301	302
Odd – Even	7.8 x 10 <sup>4</sup>	> 1.0 x 10 <sup>5</sup>	7.6 x 10 <sup>4</sup>	> 1.0 x 10 <sup>5</sup>	> 1.0 x 10 <sup>5</sup>	> 1.0 x 10 <sup>5</sup>	7.5 x 10 <sup>4</sup>	> 1.0 x 10 <sup>5</sup>
All – Sheild	5.0 x 10 <sup>4</sup>	7.2 x 10 <sup>4</sup>	3.9 x 10 <sup>4</sup>	2.2 x 10 <sup>4</sup>	6.2 x 10 <sup>4</sup>	2.5 x 10 <sup>4</sup>	4.5 x 10 <sup>4</sup>	2.1 x 10 <sup>4</sup>

## Table D.4 – Test Group 3, Insulation Resistance During Exposure (Units: Megohms)

Measurement	Cycle 1 High Temp Procedure II		Cycle 2 High Temp Procedure II		Cycle 3 High Temp Procedure II		Hour 3 Low Temp Procedure II	
10	301	302	301	302	301	302	301	302
Odd – Even	1.0x10 <sup>4</sup>	1.6 x 10 <sup>4</sup>	1.2 x 10 <sup>4</sup>	1.9 x 10 <sup>4</sup>	1.7 x 10 <sup>4</sup>	2.1 x 10 <sup>4</sup>	> 1.0 x 10 <sup>5</sup>	> 1.0 x 10 <sup>5</sup>
All – Sheild	5.8 x 10 <sup>3</sup>	8.7 x 10 <sup>3</sup>	6.3 x 10 <sup>3</sup>	9.4 x 10 <sup>3</sup>	6.7 x 10 <sup>3</sup>	9.8 x 10 <sup>3</sup>	> 1.0 x 10 <sup>5</sup>	> 1.0 x 10⁵

## Table D.5 – Test Group 4, Insulation Resistance During Exposure (Units: Megohms)

Measurement ID	Initial		Post Humidity Storage		Post Humidity Operational		Post Salt Spray		Post Strength Test	
	401	402	401	402	401	402	401	402	401	402
Odd – Even	7.4 x 10 <sup>4</sup>	2.6 x 10 <sup>4</sup>	4.4 x 10 <sup>4</sup>	1.4 x 10 <sup>4</sup>	3.4 x 10 <sup>4</sup>	1.3 x 10 <sup>4</sup>	2.2 x 10 <sup>4</sup>	1.4 x 10 <sup>4</sup>	3.4 x 10 <sup>4</sup>	5.6 x 10 <sup>3</sup>
All – Sheild	3.6 x 10 <sup>4</sup>	1.1 x 10 <sup>4</sup>	2.3 x 10 <sup>4</sup>	5.4 x 10 <sup>3</sup>	1.7 x 10 <sup>4</sup>	4.9 x 10 <sup>3</sup>	1.6 x 10 <sup>2</sup>	6.3 x 10 <sup>3</sup>	1.9 x 10 <sup>4</sup>	4.5 x 10 <sup>3</sup>



Table D.6 – Test Group 5, insulation Resistance During Exposure (Units: Megonms)								
Measurement ID	Initial @ TE Connectivity		Initial @ E-Labs_Inc		Post Rain		Post Snow & Ice	
	501	502	501	502	501	502	501	502
	301	302	301	JUZ	301	302	501	302
Odd – Even	7.3 x 10 <sup>4</sup>	7.2 x 10 <sup>4</sup>	5.8 x 10 <sup>4</sup>	5.5 x 10 <sup>4</sup>	2.4 x 10 <sup>2</sup>	5.5 x 10 <sup>3</sup>	3.1 x 10 <sup>4</sup>	3.0 x 10 <sup>4</sup>
All – Sheild	7.0 x 10 <sup>4</sup>	4.7 x 10 <sup>4</sup>	4.7 x 10 <sup>4</sup>	4.1 x 10 <sup>4</sup>	1.0 x 10 <sup>2</sup>	8.0 x 10 <sup>2</sup>	3.2 x 10 <sup>4</sup>	3.3 x 10 <sup>4</sup>
Measurement ID	Post		Post		Final			
	Solar Radiation		Dust		@ TE Connectivity			
	501	502	501	502	501	502		
Odd – Even	5.3 x 10 <sup>4</sup>	> 1.0 x 10 <sup>5</sup>	2.0 x 10 <sup>4</sup>	3.8 x 10 <sup>4</sup>	2.7 x 10 <sup>4</sup>	> 1.0 x 10 <sup>5</sup>		
All – Sheild	3.0 x 10 <sup>4</sup>	> 1.0 x 10 <sup>5</sup>	2.8 x 10 <sup>4</sup>	1.7 x 10 <sup>4</sup>	2.3 x 10 <sup>4</sup>	6.0 x 10 <sup>4</sup>		

## Appendix D – Insulation Resistance

Table D.6 – Test Group 5	Insulation Resistance Durin	q Exposure	(Units: Megohms)
	,		( J /

Note: Insulation resistance values decreased following the Rain test exposure. It was suspected that water ingress into the unsealed single-ended "pig-tail" support cable assemblies (see Figure D.1) was compromising the measurements. The support cable assemblies were unmated from the TYAD production cable assemblies under test, dried in an oven at 50°C, then remated to the test cable assemblies. Subsequent spot checks of the insulation resistance values found the results to be in line with initial measurements, confirming that the unsealed single-ended "pig-tail" support cable assemblies were the root cause of the low insulation resistance values.



Figure D.1 – Unsealed Single-Ended "Pig-Tail" Support Cable Assembly